

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/721,673	QIN ET AL.	
	Examiner Phallaka Kik	Art Unit 2825	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,818,729 A	10-1998	Wang et al.	716/9
*	B	US-6,188,974 B1	02-2001	Cullum et al.	703/14
*	C	US-6,349,272 B1	02-2002	Phillips, Joel	703/2
*	D	US-2002/0138812 A1	09-2002	Johannsen, Peer	716/5
*	E	US-2002/0147958 A1	10-2002	Teig et al.	716/12
*	F	US-2002/0198696 A1	12-2002	Sanchez et al.	703/14
*	G	US-6,581,197 B1	06-2003	Foutz et al.	716/6
*	H	US-6,609,233 B1	08-2003	Foltin et al.	716/6
*	I	US-6,604,227 B1	08-2003	Foltin et al.	716/6
*	J	US-6,687,658 B1	02-2004	Roychowdhury, Jaijeet S.	703/2
*	K	US-2004/0044979 A1	03-2004	Aji et al.	716/013
*	L	US-2004/0078767 A1	04-2004	Burks et al.	716/008
*	M	US-6,728,939 B2	04-2004	Johannsen, Peer	716/5

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003218204 A	07-2003	Japan	TSUJII, TAKAFUMI	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Pong et al., "A Parasitics Extraction and Network Reduction Algorithm for Analog VLSI", IEEE Transactions on Computer-Aided Design, Vol. 10, No. 2, February 1991, pp. 145-149.
	V	Yu et al., "New Efficient and Accurate Moment Matching Based Model For Crosstalk Estimation in Coupled RC Trees", 2001 International Symposium on Quality Electronic Design, 26 March 2001, pp. 151-157.
	W	Oten et al., "Topological Dimensionality Determination and Dimensionality Reduction Based on Minimum Spanning Trees", Proceedings of 1998 IEEE International Symposium on Circuits and Systems, 31 May 1998, Vol. 3, pp. 366-369.
	X	Hui et al., "Enhancing the Efficiency of Reduction of Large RC Networks by Pole Analysis via Congruence Transformations", Proceedings of the ASP-DAC Asia and South Pacific Design Automation Conference, Vol. 1, 18 June 1999, pp. 89-92.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/721,673	QIN ET AL.	
Examiner		Art Unit		Page 2 of 3
Phallaka Kik		2825		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,689,685 A	11-1997	Feldmann et al.	703/2
*	B	US-6,327,542 B1	12-2001	McBride, John G	702/64
*	C	US-6,353,917 B1	03-2002	Muddu et al.	716/6
*	D	US-6,510,542 B1	01-2003	Kojima, Naohito	716/10
*	E	US-2003/0121013 A1	06-2003	Moon et al.	716/6
*	F	US-2003/0115557 A1	06-2003	Elzinga, Mark	716/4
*	G	US-6,601,223 B1	07-2003	Puri et al.	716/6
*	H	US-2003/0125919 A1	07-2003	Chikamichi, Shoichi	703/14
*	I	US-2003/0204821 A1	10-2003	Weber, Larren Gene	716/1
*	J	US-6,662,149 B1	12-2003	Devgan et al.	703/14
*	K	US-2004/0103386 A1	05-2004	Becer et al.	716/013
*	L	US-2005/0021319 A1	01-2005	Li et al.	703/002
*	M	US-7,024,652 B1	04-2006	McGaughy et al.	716/12

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Harbour et al., "Simple RC Model for Integrated Multiterminal Interconnections", IEE Proceedings of Circuits, Devices and Systems, Vol. 135, No. 1, February 1988, pp. 19-23.
	V	Zheng et al., "Efficient and Accurate Modeling of Power Supply Noise on Distributed On-Chip Power Networks", IEEE International Symposium on Circuits and Systems, 28-31 May, 2000, pp. II-513-516.
	W	Chen et al., "A Novel Method for Worst-Case Interconnect Delay Estimation", IEEE Transactions on Circuits and Systems--I: Fundamental Theory and Applications, Vol. 50, No. 6, June 2003, pp. 778-781.
	X	Liao et al., "Partitioning and Reduction of RC Interconnect Networks Based on Scattering Parameter Macromodels", 1995 IEEE/ACM International Conference on Computer-Aided Design, 5-9 November 1995, pp. 704-709.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/721,673	QIN ET AL.	
Examiner		Art Unit	Phallaka Kik	
		2825	Page 3 of 3	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,901,063 A	05-1999	Chang et al.	716/4
*	B	US-6,286,126 B1	09-2001	Raghavan et al.	716/6
*	C	US-2004/0049746 A1	03-2004	Rao et al.	716/004
*	D	US-6,928,630 B2	08-2005	Moon et al.	716/6
*	E	US-2006/0010412 A1	01-2006	Teig et al.	716/008
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Batterywala et al., "Time Domain Method for Reduced Order Network Synthesis of Large RC Circuits", Proceedings of the 1998 IEEE International Symposium on Circuits and Systems, Vol. 6, 31 May 1998, pp. 82-85.
	V	Hou et al., "Improved Delay Time Estimation of RC Ladder Networks", IEEE Transactions on Circuits and Systems I: Fundamental Theory and Applications, Vol. 47, No. 2, February 2000, pp. 242-246.
	W	Kerns et al., "Stable and Efficient Reduction of Large, Multiport RC Networks by Pole Analysis via Congruence Transformations", IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 16, No. 7, July 1997, pp. 734-744.
	X	Schroter, "Simulation and Modeling of the Low-Frequency Base Resistance of Bipolar Transistors and Its Dependence of Current and Geometry", IEEE Transactions on Electron Devices, Vol. 38, No. 3, March 1991, pp. 538-544.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.